

40V N-Channel Enhancement Mode MOSFET

Description

The AP100N04NF uses advanced **APM-SGT II** technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

$V_{DS} = 40V$ $I_D = 100A$

$R_{DS(ON)} < 3.2m\Omega$ @ $V_{GS}=10V$ (Type: **2.1mΩ**)

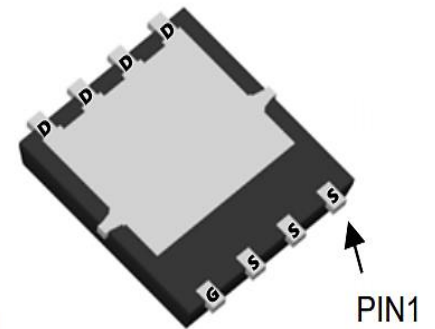
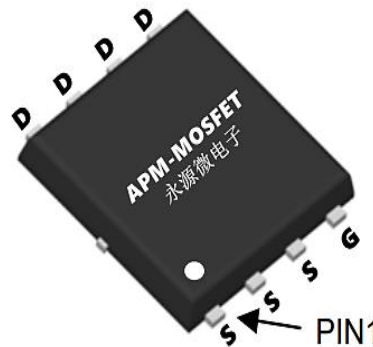
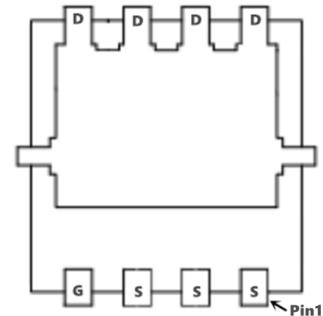
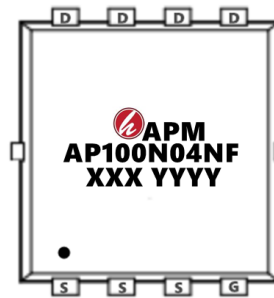
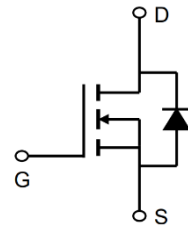
$C_{iss} \approx 2600PF$

Application

Boost driver

Brushless motor

BLDC



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP100N04NF	DFN5*6-8L	AP100N04NF XXX YYYY	5000

Absolute Maximum Ratings ($T_C=25^\circ C$ unless otherwise noted)

Symbol	Parameter	Rating	Units
VDS	Drain-Source Voltage	40	V
VGS	Gate-Source Voltage	± 20	V
ID@TC=25°C	Continuous Drain Current, VGS @ 10V1	100	A
ID@TC=100°C	Continuous Drain Current, VGS @ 10V1	71	A
IDM	Pulsed Drain Current ²	240	A
EAS	Single Pulse Avalanche Energy ³	345	mJ
IAS	Avalanche Current	54	A
PD@TC=25°C	Total Power Dissipation ⁴	22	W
TSTG	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C
RθJA	Thermal Resistance Junction-Ambient 1	25	°C/W
RθJC	Thermal Resistance Junction-Case ¹	1.7	°C/W

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Electrical Characteristics ($T_J=25^\circ\text{C}$, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	40	44	---	V
RDS(ON)	Static Drain-Source On-Resistance ²	$V_{GS}=10V, I_D=20A$	---	2.1	3.2	m Ω
		$V_{GS}=4.5V, I_D=15A$	---	2.7	5.3	
VGS(th)	Gate Threshold Voltage	$V_{GS}=V_{DS}, I_D=250\mu A$	1.2	1.7	2.5	V
IDSS	Drain-Source Leakage Current	$V_{DS}=40V, V_{GS}=0V, T_J=25^\circ\text{C}$	---	---	1	uA
IDSS	Drain-Source Leakage Current	$V_{DS}=40V, V_{GS}=0V, T_J=55^\circ\text{C}$	---	---	5	
IGSS	Gate-Source Leakage Current	$V_{GS}=\pm 20V, V_{DS}=0V$	---	---	± 100	nA
gfs	Forward Transconductance	$V_{DS}=5V, I_D=20A$	---	75	---	S
Rg	Gate Resistance	$V_{DS}=0V, V_{GS}=0V, f=1\text{MHz}$	---	1.5	---	Ω
Qg	Total Gate Charge (4.5V)	$V_{DS}=20V, V_{GS}=4.5V, I_D=20A$	---	22.7	---	nC
Qgs	Gate-Source Charge		---	7.5	---	
Qgd	Gate-Drain Charge		---	5.5	---	
Td(on)	Turn-On Delay Time	$V_{DD}=20V, V_{GS}=10V, R_G=3\Omega, I_D=20A$	---	10	---	ns
Tr	Rise Time		---	5	---	
Td(off)	Turn-Off Delay Time		---	33	---	
Tf	Fall Time		---	6.5	---	
Ciss	Input Capacitance	$V_{DS}=20V, V_{GS}=0V, f=1\text{MHz}$	---	2600	---	pF
Coss	Output Capacitance		---	899	---	
Crss	Reverse Transfer Capacitance		---	71	---	
IS	Continuous Source Current ^{1,5}	$V_G=V_D=0V, \text{Force Current}$	---	---	30	A
VSD	Diode Forward Voltage ²	$V_{GS}=0V, I_S=1A, T_J=25^\circ\text{C}$	---	---	1	V

Note :

- 1、The data tested by surface mounted on a 1 inch 2 FR-4 board with 2OZ copper.
- 2、The data tested by pulsed , pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$
- 3、The EAS data shows Max. rating . The test condition is $V_{DD}=32V, V_{GS}=10V, L=0.1\text{mH}, I_{AS}=54A$
- 4、The power dissipation is limited by 150°C junction temperature
- 5、The data is theoretically the same as I D and I DM , in real applications , should be limited by total power dissipation.

Typical Characteristics

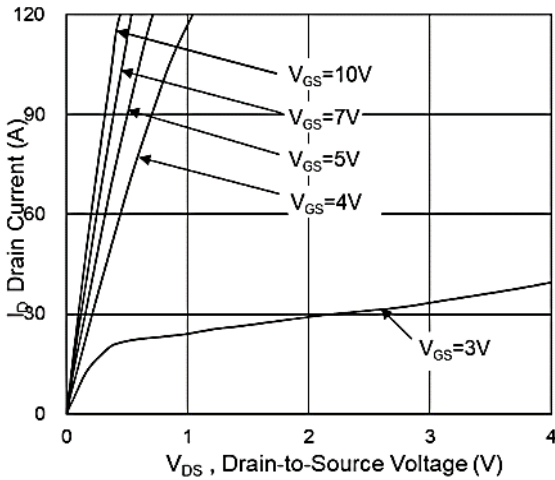


Fig.1 Typical Output Characteristics

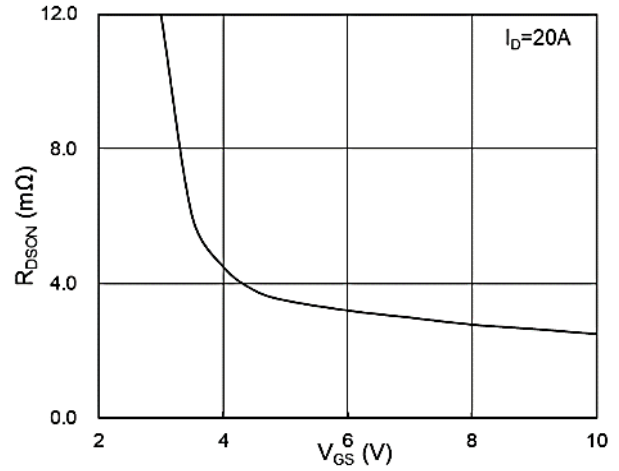


Fig.2 On-Resistance vs G-S Voltage

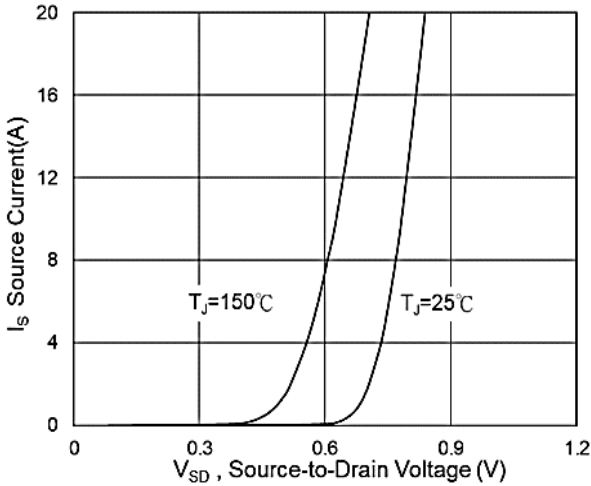


Fig.3 Source Drain Forward Characteristics

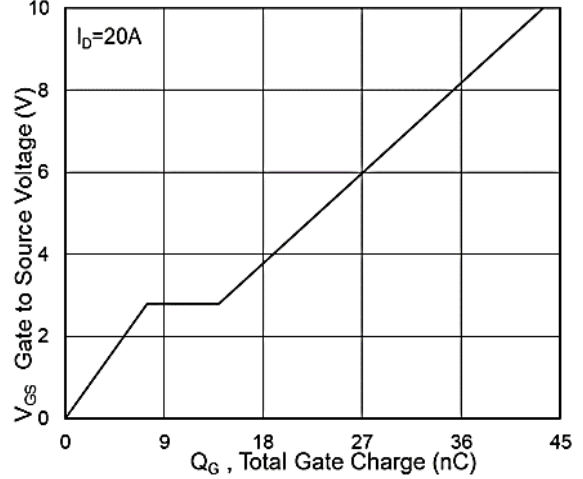


Fig.4 Gate-Charge Characteristics

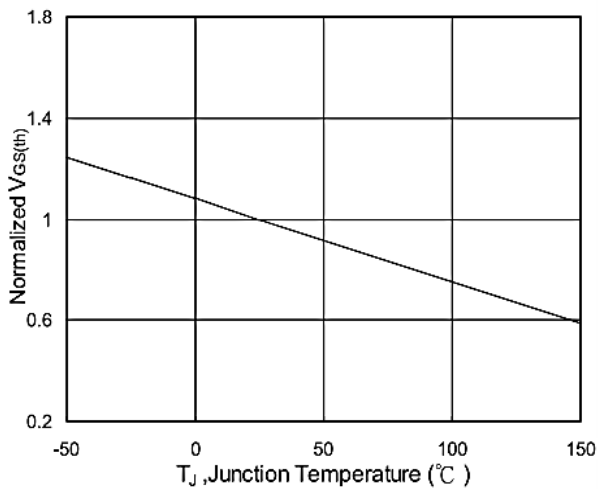


Fig.5 Normalized $V_{GS(th)}$ vs T_J

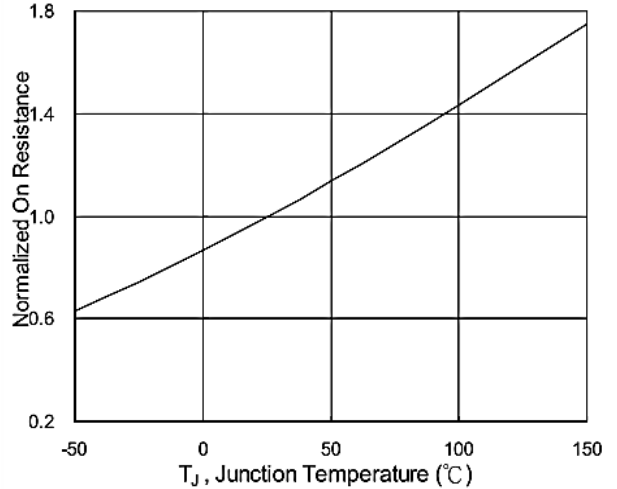


Fig.6 Normalized $R_{DS(on)}$ vs T_J

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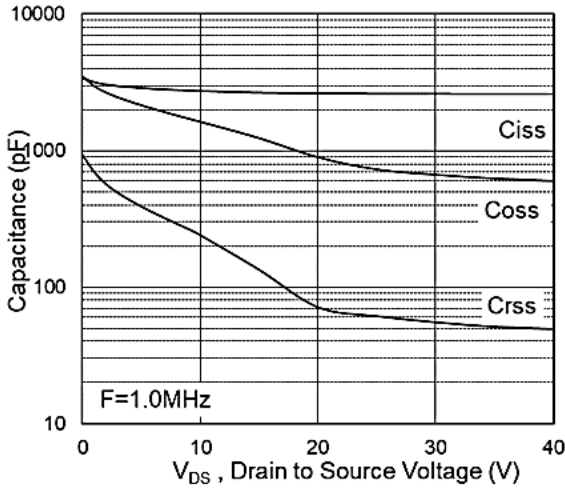


Fig.7 Capacitance

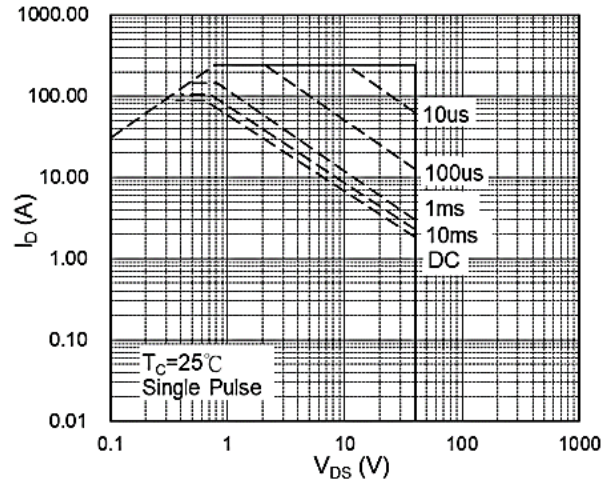


Fig.8 Safe Operating Area

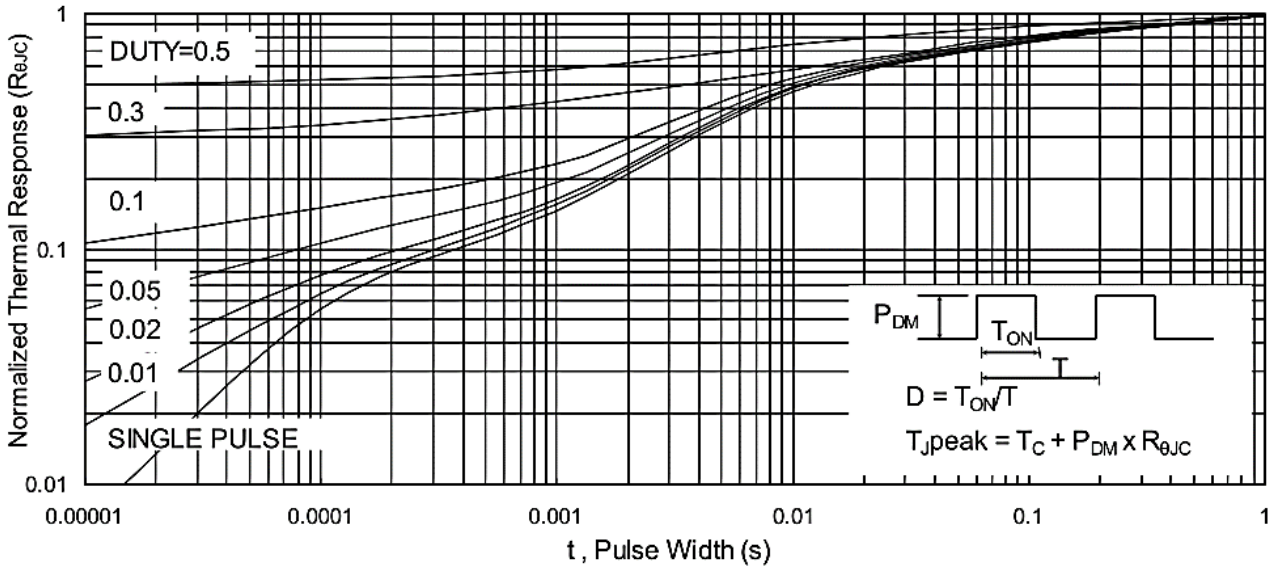


Fig.9 Normalized Maximum Transient Thermal Impedance

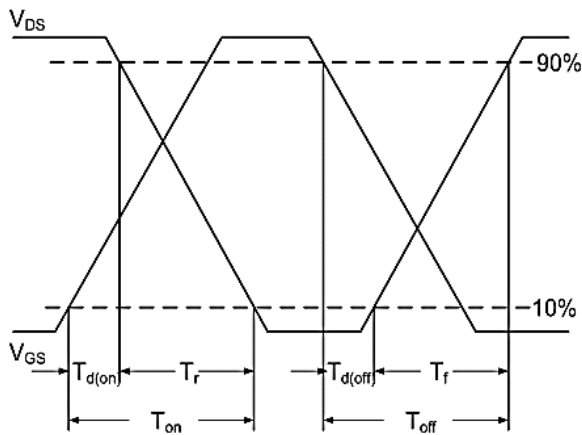


Fig.10 Switching Time Waveform

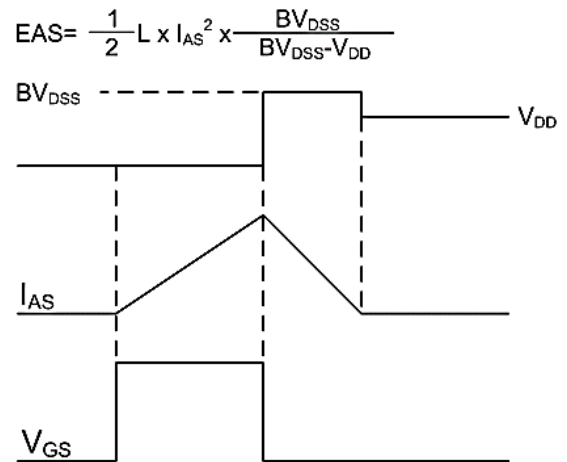
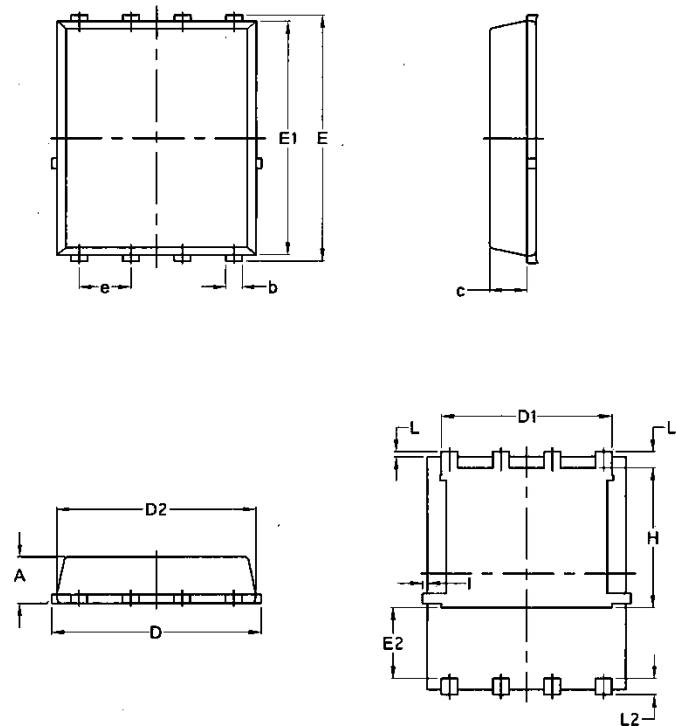


Fig.11 Unclamped Inductive Switching Wave

Package Mechanical Data-PDFN5*6-8L-JQ Single



Symbol	Common			
	mm		Inch	
	Min	Max	Min	Max
A	1.03	1.17	0.0406	0.0461
b	0.34	0.48	0.0134	0.0189
c	0.824	0.0970	0.0324	0.082
D	4.80	5.40	0.1890	0.2126
D1	4.11	4.31	0.1618	0.1697
D2	4.80	5.00	0.1890	0.1969
E	5.95	6.15	0.2343	0.2421
E1	5.65	5.85	0.2224	0.2303
E2	1.60	/	0.0630	/
e	1.27 BSC		0.05 BSC	
L	0.05	0.25	0.0020	0.0098
L1	0.38	0.50	0.0150	0.0197
L2	0.38	0.50	0.0150	0.0197
H	3.30	3.50	0.1299	0.1378
I	/	0.18	/	0.0070

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Edition	Date	Change
Rev1.0	2021/9/31	Initial release
Rev1.1	2021/4/20	Reduce(RDS)

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